

10/533645

JC20 Rec'd PCT/PTO 03 MAY 2005

PATENT
3511-1003

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Iiro HIETANEN et al.

Conf.

Application No. **NEW NATIONAL PHASE**

Group

Filed May 3, 2005

Examiner

SYNCHRONOUS OPTICAL MEASUREMENT AND INSPECTION METHOD AND MEANS

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

May 3, 2005

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begin on page 3 of this paper.

Remarks begin on page 10 of this paper.

An **Appendix** is attached following the signature page of this paper.